

<b>Notice of References Cited</b>	Application/Control No. 09/852,899	Applicant(s)/Patent Under Reexamination SHORT, ALVIN P.
	Examiner Anh D. Mai	Art Unit 2814

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5677225	10-1997	Park	438/386
B	US-6077739	06-2000	Chang	438/386
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U	T. Hamamoto et al., Trench-Trench Leakage Current Characteristics in the Stacked Trench Capacitor (STT) Cell. IEEE 1991, pp. 419-422.		
V			
W			
X			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.